

PTO/SB/08a (08-03)

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 3

Complete if Known

Application Number	10/803,867
Filing Date	March 18, 2004
First Named Inventor	Brooks, et al.
Art Unit	1756
Examiner Name	Unknown Young
Attorney Docket Number	AMAT/7681/MASK/MASK-TECH/ARNOLD S

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
Cuy	A1	US-6,709,901	03/23/2004	Yamazaki et al.	
Cuy	A2	US-6,635,185	10/21/2003	Demmin et al.	
Cuy	A3	US-6,391,791	05/21/2002	Sasaki et al.	
Cuy	A4	US-6,307,265	03/14/2000	Mui et al.	
Cuy	A5	US-6,251,217	06/26/2001	Ye et al.	
Cuy	A6	US-6,214,637	04/10/2001	Kim et al.	
Cuy	A7	US-6,114,250	09/05/2000	Ellingboe et al.	
Cuy	A8	US-6,080,529	06/27/2000	Ye et al.	
Cuy	A9	US-6,033,979	03/07/2000	Endo	
Cuy	A10	US-6,007,732	12/28/1999	Hashimoto et al.	
Cuy	A11	US-5,994,235	11/30/1999	O'Donnell	
Cuy	A12	US-5,948,570	09/07/1999	Kornblit et al.	
Cuy	A13	US-5,861,233	01/19/1999	Sekine et al.	
Cuy	A14	US-5,773,199	06/30/1998	Linliu et al.	
Cuy	A15	US-5,750,290	05/12/1998	Yasuzato et al.	
Cuy	A16	US-5,538,816	07/23/1996	Hashimoto et al.	
Cuy	A17	US-4,600,686	07/15/1986	Meyer et al.	
Cuy	A18	US-4,504,574	03/12/1985	Meyer et al.	
Cuy	A19	US-4,406,733	09/27/1983	Tachi et al.	
Cuy	A20	US-4,350,563	09/21/1982	Takada et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				
Cuy	B1	DE 27 01 458	01/14/1977	Sato et al.		
Cuy	B2	EP 0 978 870	02/09/2000	Sasaki et al.		
Cuy	B3	EP 0 999 472	05/10/2000	Sasaki et al.		
Cuy	B4	JP 11-131263 (English abstract)	05/18/1999	Shusaku		X
Cuy	B5	JP 2001-33940 (English abstract)	06/10/2003	Yong-Hoon		X
Cuy	B6	JP 60 016422 (English abstract)	01/28/1985	Hidefumi et al.		X
Cuy	B7	JP 60 219748 (English abstract)	11/02/1985	Kazuhiro et al.		X
Cuy	B8	JP 62 181433 (English abstract)	08/08/1987	Kazuhiro et al.		X
Cuy	B9	WO 00/67281	11/09/2000	Pong		

Examiner Signature		Date Considered	2/2005
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**SUPPLEMENTAL
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet	2	of	3
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Complete if Known

Application Number	10/803,867
Filing Date	March 18, 2004
First Named Inventor	Brooks, et al.
Art Unit	1756
Examiner Name	Unknown Young
Attorney Docket Number	AMAT77681/MASK/MASK-TECH/ARNOLD S

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

[illegible]

**Examiner
Signature**

Date Considered

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Substitute for form 1449B/PTO		Complete If Known	
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/803,867
		Filing Date	March 18, 2004
		First Named Inventor	Brooks, et al.
		Art Unit	1756
		Examiner Name	Unknown Young
Sheet 3 of 3	Attorney Docket Number	AMAT/7681/MASK/MASK-TECH/ARNOLD S	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
Cuy	C1	PCT International Search Report from International Application No. PCT/US02/27869, Dated 23 December 2002. (AMAT/6399PCT).	
Cuy	C2	PCT Search Report for PCT/US03/11549, dated February 19, 2004 (AMAT/6991.PCT).	
Cuy	C3	KWON, ET AL., "Loading Effect Parameters at Dry Etcher System and Their Analysis at Mask-to-Mask Loading and Within-Mask Loading" Proceedings of SPIE, Vol. 4562 (2002) pp. 79-87.	
Cuy	C4	FUJISAWA, ET AL. "Evaluation of NLD Mask Dry Etching System" SPIE Symposium on Photomask and X-Ray Technology VI, Yokohama, JAPAN, September (1999) Vol. 3748 pp. 147-152.	
Cuy	C5	RUHL, ET AL. "Chrome Dry Etch Process Characterization Using Surface Nano Profiling" Proceedings of SPIE, Vol. 4186 (2001) pp. 97-107.	
Cuy	C6	AOYAMA, ET AL. "Advanced Cr Dry Etching Process" SPIE Symposium on Photomask and X-Ray Technology VI, Yokohama, JAPAN, September (1999) SPIE, Vol. 3748 pp. 137-146.	

Examiner Signature		Date Considered	2/2005
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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet

1

of

1

Application Number

10/803,867

Filing Date

MARCH 18, 2004

First Named Inventor

BROOKS, ET AL.

Group Art Unit

UNKNOWN 1756

Examiner Name

UNKNOWN Young

Attorney Docket Number

AMAT/7681/MASK/MASK-ETCH/ARNOLD S

Submission Date

06/17, 2004

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	A1	US-6,251,217	06/20/2001	Ye, et al.	
	A2	US-6,214,637	04/10/2001	Kim, et al.	
	A3	US-6,114,250	09/05/2000	Ellingbee, et al.	
	A4	US-6,080,529	06/27/2000	Ye, et al.	
	A5	US-6,037,266	08/14/2000	Mul, et al.	
	A6	US-6,033,979	03/07/2000	Endo	
	A7	US-6,007,732	12/29/1999	Hashimoto, et al.	
	A8	US-5,948,570	09/07/1999	Kornblit, et al.	
	A9	US-5,861,299	01/19/1999	Gekins, et al.	
	A10	US-5,773,199	08/30/1998	Linlu, et al.	
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	A12	US-5,338,816	7/23/1998	Hashimoto, et al.	
	A13	US-4,600,686	07/16/1986	Meyer, et al.	
	A14	US-4,504,574	03/12/1985	Mayer, et al.	
	A15	US-			
	A16	US-			
	A17	US-			
	A18	US-			

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	B1	JP 60-016422 (Eng. Abstract)	01/28/1985	Nakada Hidefumi, et al.		X
	B2					
	B3					
	B4					
	B5					

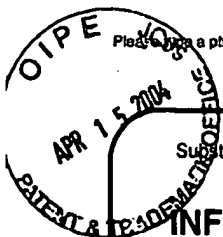
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10/803,867

Filing Date

MARCH 18, 2004

First Named Inventor

BROOKS, ET AL

Group Art Unit

~~UNKNOWN~~ 1756

Examiner Name

~~UNKNOWN~~ Young

Attorney Docket Number

AMAT/7681/MASK/MASK-ETCH/ARNOLD S

Submission Date

April 12, 2004

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
	A1	PCT Search Report for PCT/US03/11549, dated February 19, 2004 (AMAT/6991.PG)	
	A2	KWON, ET AL., "Loading Effect Parameters at Dry Etcher System and Their Analysis at Mask-to-Mask Loading and Within-Mask Loading" Proceedings of SPIE, Vol. 4562 (2002) pp. 79-87.	
	A3	FUJISAWA, ET AL. "Evaluation of NLD Mask Dry Etching System" SPIE-Symposium on Photomask and X-Ray Technology VI, Yokohama, JAPAN, September (1999) Vol. 3748 pp. 147-152.	
	A4	RUHL, ET AL. "Chrome Dry Etch Process Characterization Using Surface Nano Profiling" Proceedings of SPIE, Vol. 4186 (2001) pp. 97-107.	
	A5	AOYAMA, ET AL. "Advanced Cr Dry Etching Process" SPIE Symposium on Photomask and X-Ray Technology VI, Yokohama, JAPAN, September (1999) SPIE, Vol. 3748 pp. 137-146.	

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